

<b>Notice of References Cited</b>	Application/Control No. 10/050,334		Applicant(s)/Patent Under Reexamination AGARWAL ET AL.	
	Examiner Tuan H. Nguyen		Art Unit 2813	Page 1 of 1

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*	B	US-5,006,956	04-1991	Kawakita et al.	361/321.5
*	C	US-6,780,704	08-2004	Raaijmakers et al.	438/239
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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